

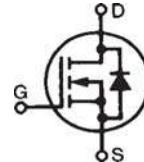
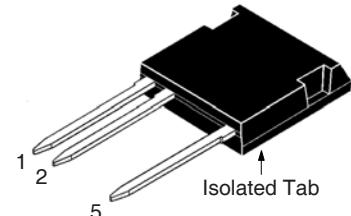
Polar3™
High Voltage
Power MOSFET

IXTF2N300P3

V_{DSS} = 3000V
I_{D25} = 1.60A
R_{DS(on)} ≤ 21Ω

(Electrically Isolated Tab)

N-Channel Enhancement Mode

**ISOPLUS i4-Pak™**

1 = Gate 5 = Drain
 2 = Source

Symbol	Test Conditions	Maximum Ratings	
V _{DSS}	T _J = 25°C to 150°C	3000	V
V _{DGR}	T _J = 25°C to 150°C, R _{GS} = 1MΩ	3000	V
V _{GSS}	Continuous	±20	V
V _{GSM}	Transient	±30	V
I _{D25}	T _C = 25°C	1.60	A
I _{D110}	T _C = 110°C	0.90	A
I _{DM}	T _C = 25°C, Pulse Width Limited by T _{JM}	6.00	A
P _D	T _C = 25°C	160	W
T _J		- 55 ... +150	°C
T _{JM}		150	°C
T _{stg}		- 55 ... +150	°C
T _L	Maximum Lead Temperature for Soldering Plastic Body for 10s	300	°C
T _{SOLD}		260	°C
F _c	Mounting Force	20..120 / 4.5..27	N/lb
V _{ISOL}	50/60Hz, 1 Minute	3000	V~
Weight		6	g

Symbol	Test Conditions (T _J = 25°C, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
BV _{DSS}	V _{GS} = 0V, I _D = 250μA	3000		V
V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250μA	3.0		5.0 V
I _{GSS}	V _{GS} = ±20V, V _{DS} = 0V		±100	nA
I _{DSS}	V _{DS} = V _{DSS} , V _{GS} = 0V Note 2, T _J = 125°C		10	μA
			500	μA
R _{DS(on)}	V _{GS} = 10V, I _D = 1A, Note 1		21	Ω

Features

- Silicon Chip on Direct-Copper Bond (DCB) Substrate
- Isolated Mounting Surface
- 3000V~ Electrical Isolation
- High Blocking Voltage
- High Voltage Package

Advantages

- Easy to Mount
- Space Savings
- High Power Density

Applications

- High Voltage Power Supplies
- Capacitor Discharge Applications
- Pulse Circuits
- Laser and X-Ray Generation Systems

Symbol	Test Conditions (T _J = 25°C, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
g_{fs}	V _{DS} = 50V, I _D = 1A, Note 1	1.8	3.0	S
C_{iss}	V _{GS} = 0V, V _{DS} = 25V, f = 1MHz	1890		pF
C_{oss}		90		pF
C_{rss}		42		pF
R_{Gi}	Gate Input Resistance	7.7		Ω
t_{d(on)}	Resistive Switching Times V _{GS} = 10V, V _{DS} = 500V, I _D = 1A R _G = 5Ω (External)	21		ns
t_r		17		ns
t_{d(off)}		69		ns
t_f		62		ns
Q_{g(on)}	V _{GS} = 10V, V _{DS} = 1.5kV, I _D = 1A	73		nC
Q_{gs}		9		nC
Q_{gd}		40		nC
R_{thJC}			0.77 °C/W	
R_{thCS}		0.15		°C/W

Source-Drain Diode

Symbol	Test Conditions (T _J = 25°C, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
I_s	V _{GS} = 0V		2.0	A
I_{SM}	Repetitive, Pulse Width Limited by T _{JM}		8.0	A
V_{SD}	I _F = I _S , V _{GS} = 0V, Note 1		1.5	V
t_{rr}	I _F = 1A, -di/dt = 100A/μs V _R = 100V, V _{GS} = 0V	400		ns
Q_{RM}		250		nC
I_{RM}		1.3		A

Notes:

1. Pulse test, t ≤ 300μs, duty cycle, d ≤ 2%.
2. Device must be heatsunk for high-temperature leakage current measurements to avoid thermal runaway.

ADVANCE TECHNICAL INFORMATION

The product presented herein is under development. The Technical Specifications offered are derived from a subjective evaluation of the design, based upon prior knowledge and experience, and constitute a "considered reflection" of the anticipated result. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

IXYS Reserves the Right to Change Limits, Test Conditions, and Dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,931,844 5,049,961 5,237,481 6,162,665 6,404,065 B1 6,683,344 6,727,585 7,005,734 B2 7,157,338B2 4,860,072 5,017,508 5,063,307 5,381,025 6,259,123 B1 6,534,343 6,710,405 B2 6,759,692 7,063,975 B2 4,881,106 5,034,796 5,187,117 5,486,715 6,306,728 B1 6,583,505 6,710,463 6,771,478 B2 7,071,537

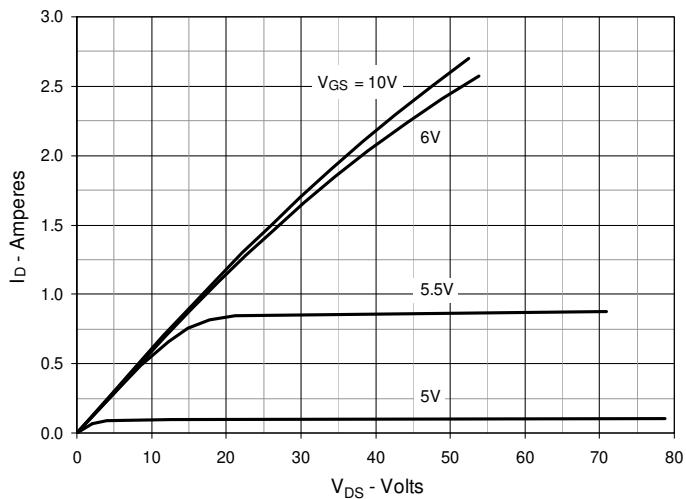
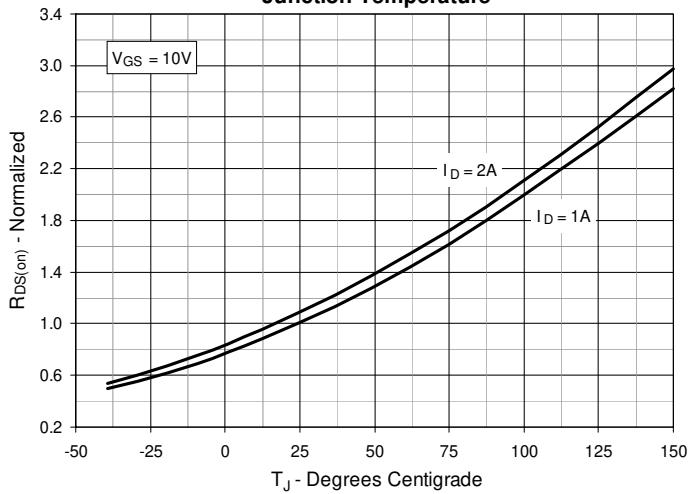
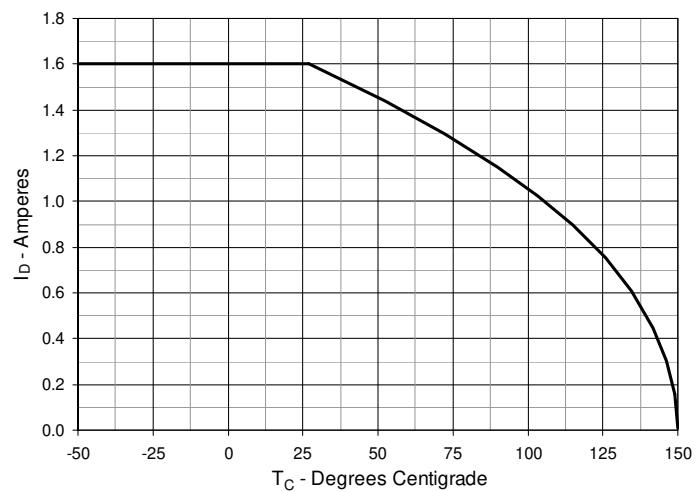
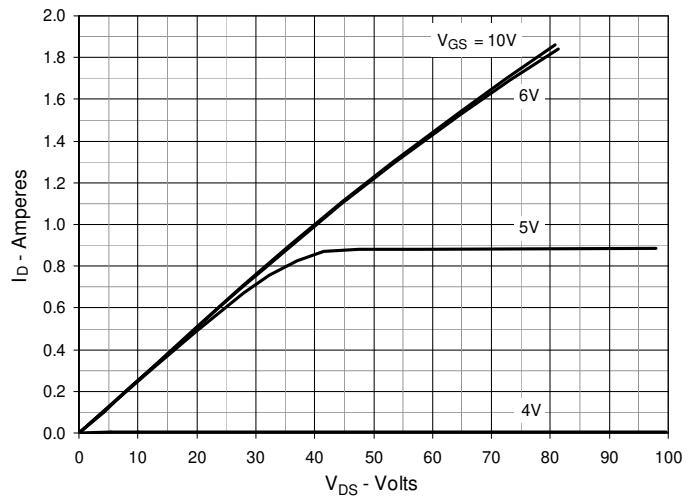
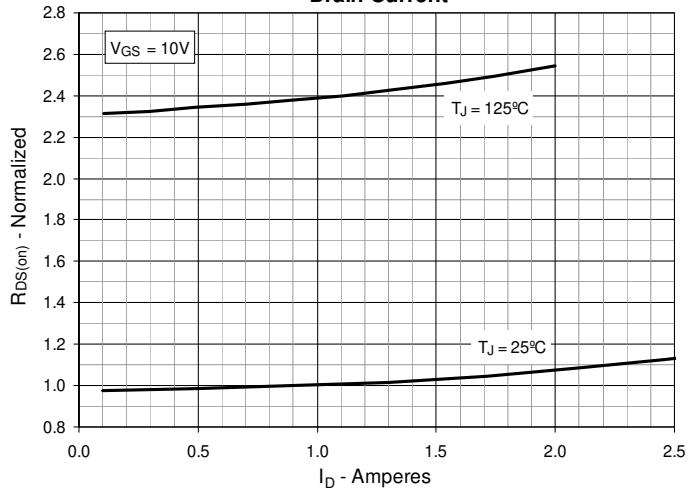
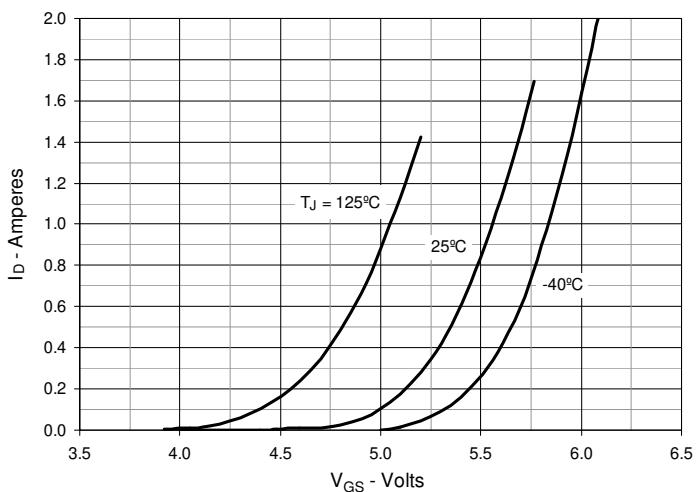
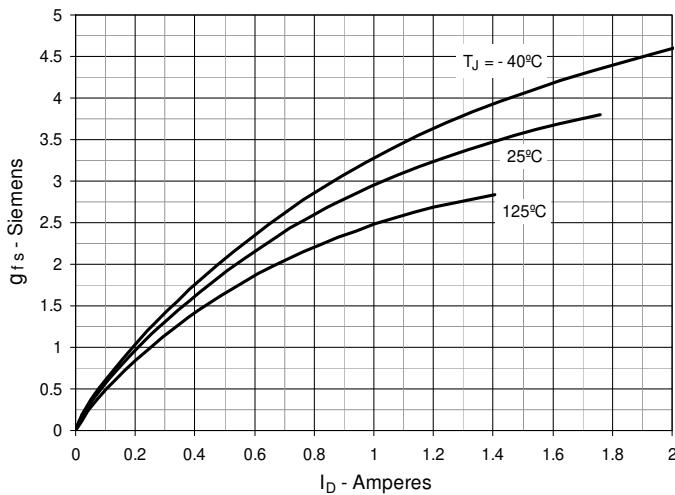
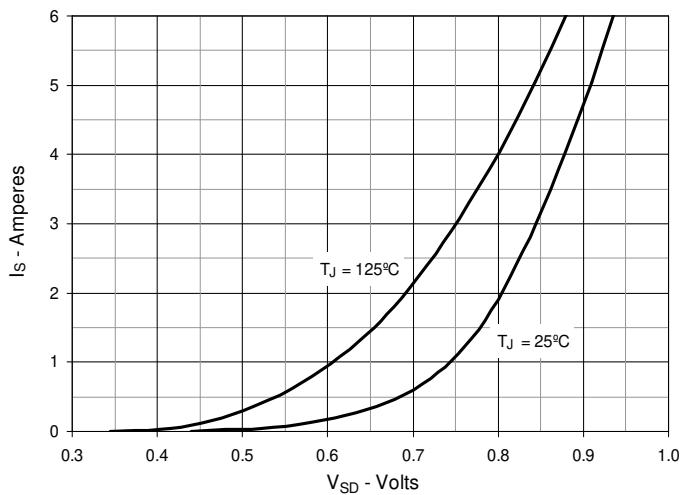
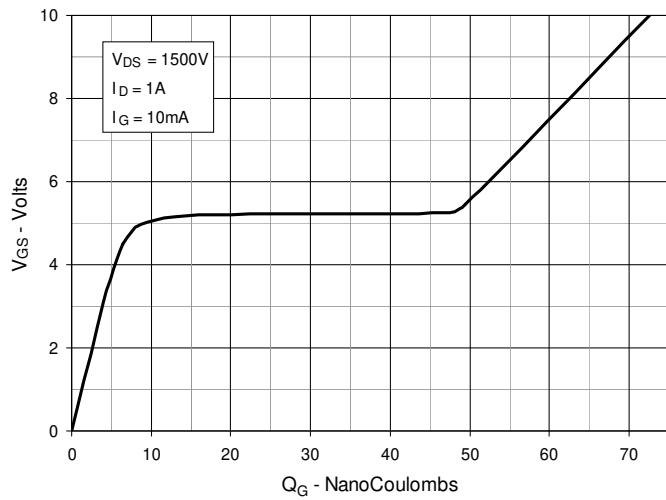
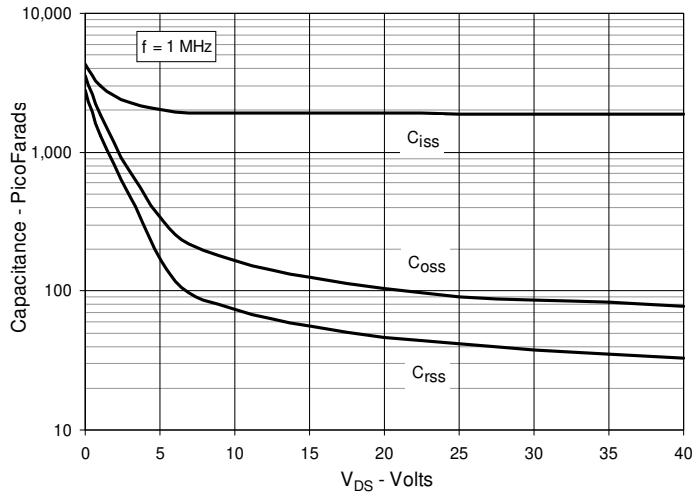
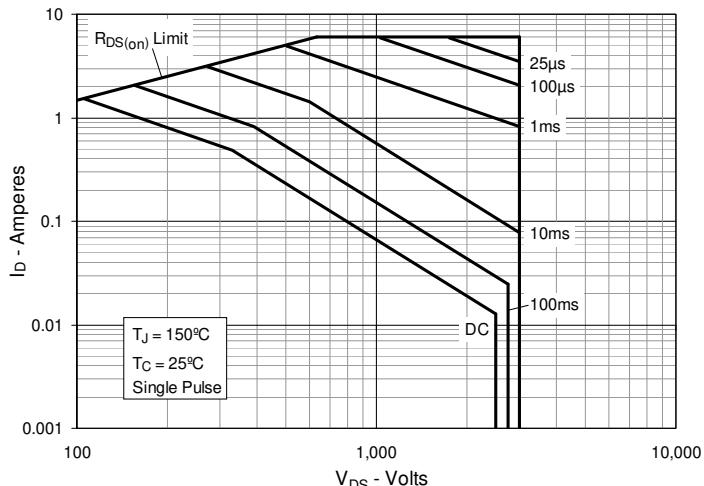
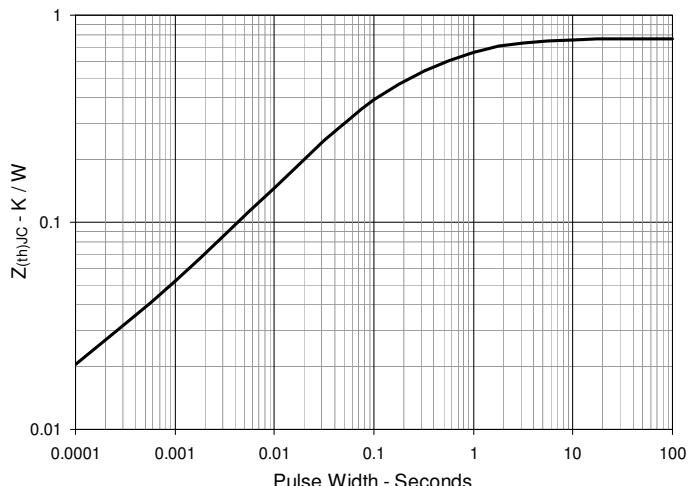
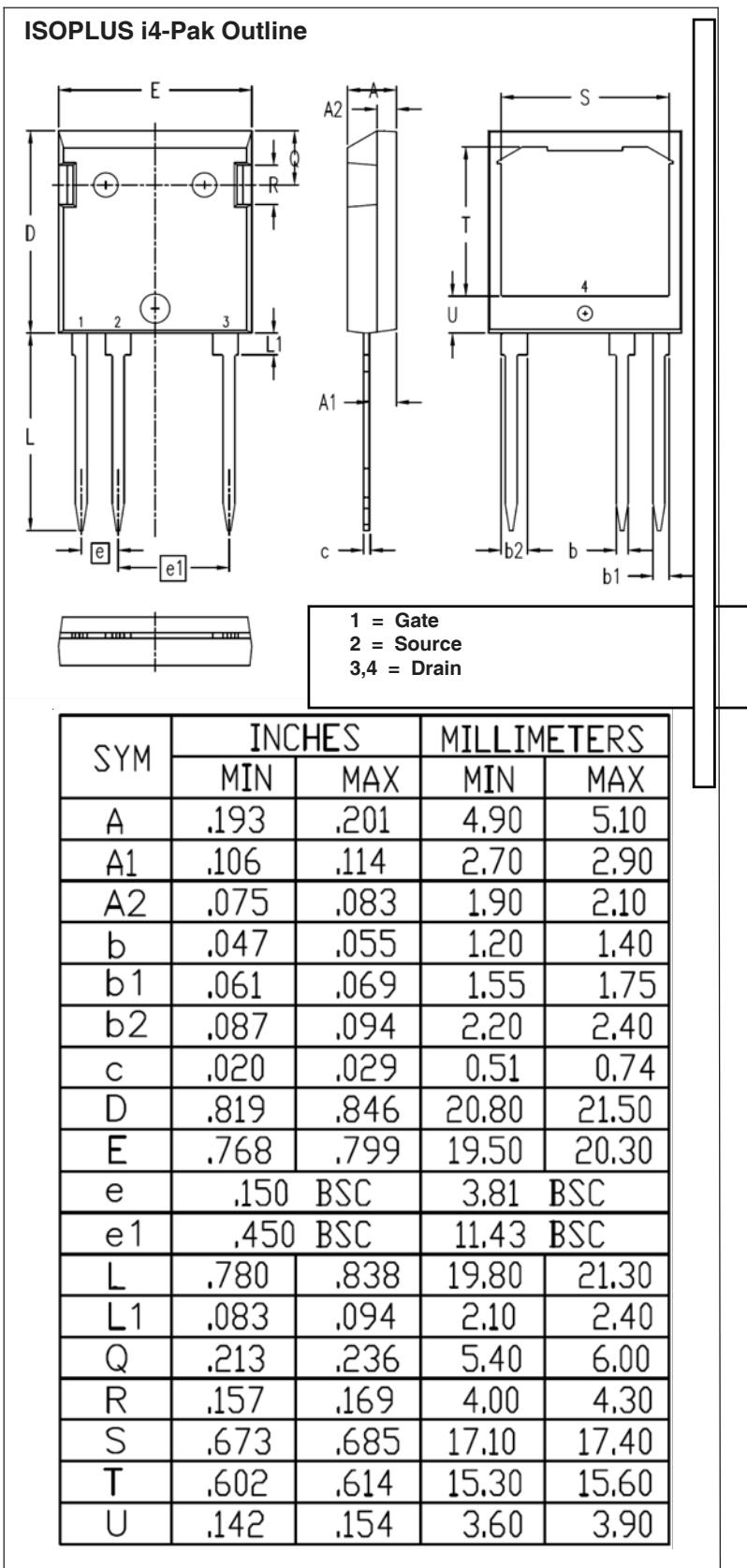
Fig. 1. Output Characteristics @ $T_J = 25^\circ\text{C}$ **Fig. 3. $R_{DS(on)}$ Normalized to $I_D = 1\text{A}$ Value vs. Junction Temperature****Fig. 5. Maximum Drain Current vs. Case Temperature****Fig. 2. Output Characteristics @ $T_J = 125^\circ\text{C}$** **Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 1\text{A}$ Value vs. Drain Current****Fig. 6. Input Admittance**

Fig. 7. Transconductance**Fig. 8. Forward Voltage Drop of Intrinsic Diode****Fig. 9. Gate Charge****Fig. 10. Capacitance****Fig. 11. Forward-Bias Safe Operating Area****Fig. 12. Maximum Transient Thermal Impedance**

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